

| | | | |
|-----------------------------------|-------------------------|---|-------------|
| Notice of References Cited | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | 09/385,666 | SUAYA ET AL. | |
| | Examiner | Art Unit | |
| | Thai Q. Phan | 2128 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------|----------------|
| | A | US- | | | |
| | B | US- | | | |
| | C | US- | | | |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | | | | |
|---|---|---|--|--|--|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
| * | U | Chen et al, "An On-Chip, Attofarad Interconnect Charge-based Capacitance Measurement Technique", IEEE, 1996, pp. 3.4.1-3.4.4. | | | |
| * | V | Sylvester et al, "Investigation of Interconnect Capacitance Characterization using Charge-based Capacitance Measurement Technique and 3-D Simulation", IEEE, 1997, pp. 491-494. | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.